

## HF20D060ACE

### Hexfred Die in Wafer Form

#### Features

- GEN3 Hexfred Technology
- Low  $V_F$
- Low  $I_{RR}$
- Low  $t_{RR}$
- Soft Reverse Recovery

#### Benefits

- Benchmark Efficiency for Motor Control Applications
- Rugged Transient Performance
- Low EMI
- Excellent Current Sharing in Parallel Operation
- Qualified for Industrial Market

600V  
 $I_{F(nom)} = 20A$   
 $V_{F(typ)} = 1.2V @ I_{F(nom)} @ 25^\circ C$   
 Motor Control Antiparallel Diode  
 125mm Wafer

#### Electrical Characteristics (Wafer Form)

| Parameter | Description               | Guaranteed (min, max) | Test Conditions                |
|-----------|---------------------------|-----------------------|--------------------------------|
| $V_F$     | Forward Voltage Drop      | 0.85V min, 1.15V max  | $I_C = 4A, T_J = 25^\circ C$   |
| $BV_R$    | Reverse Breakdown Voltage | 600V min              | $T_J = 25^\circ C, I_R = 1mA$  |
| $I_{RM}$  | Reverse Leakage Current   | 20 $\mu A$ max        | $T_J = 25^\circ C, V_R = 600V$ |

#### Mechanical Data

|                                              |                                                                                         |
|----------------------------------------------|-----------------------------------------------------------------------------------------|
| Nominal Backmetal Composition, (Thickness)   | Cr- Ni - Ag, (1kA - 4kA - 6kA)                                                          |
| Nominal Front Metal Composition, (Thickness) | 99% Al/1% Si, (3 $\mu m$ )                                                              |
| Dimensions                                   | 0.085" x 0.165"                                                                         |
| Wafer Diameter                               | 125mm, with std. < 100 > flat                                                           |
| Wafer Thickness, Tolerance                   | 381 $\mu m$ , +/-15 $\mu m$                                                             |
| Relevant Die Mechanical Dwg. Number          | 01-5510                                                                                 |
| Minimum Street Width                         | 100 $\mu m$                                                                             |
| Reject Ink Dot Size                          | 0.25mm diameter minimum                                                                 |
| Ink Dot Location                             | Consistent throughout same wafer lot                                                    |
| Recommended Storage Environment              | Store in original container, in dessicated nitrogen, with no contamination              |
| Recommended Die Attach Conditions            | For optimum electrical results, die attach temperature should not exceed 300 $^\circ C$ |

#### Die Outline

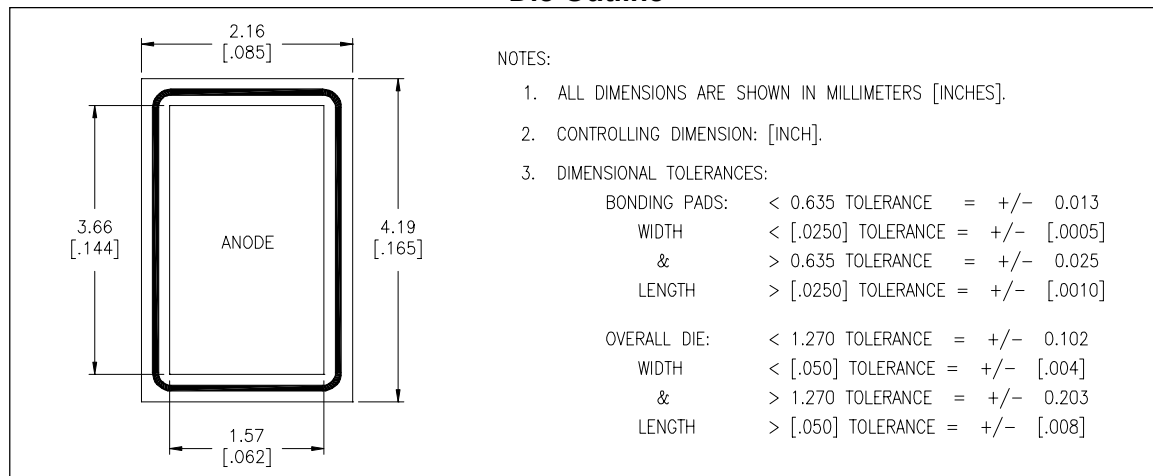


Fig. 1 - Typical Diode Recovery Waveform

$V_{CC} = 400V$ ;  $R_g = 22\ \Omega$ ;  $T_j = 150^\circ C$

$L = 200\mu H$ ; Driver = IRGP20B60K-E

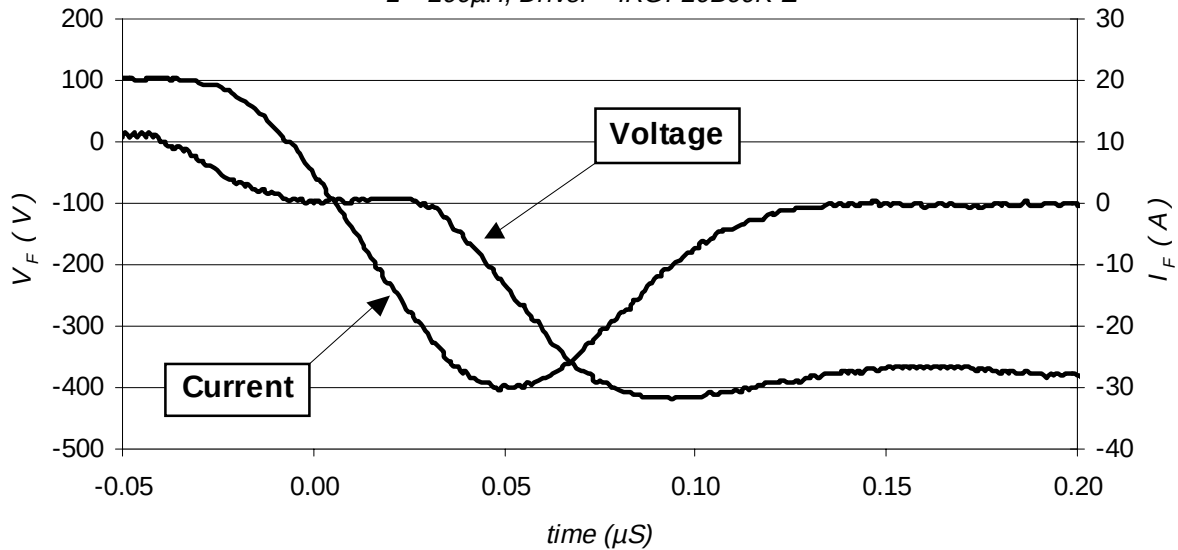


Fig. 2 - Typical Diode Forward Characteristics

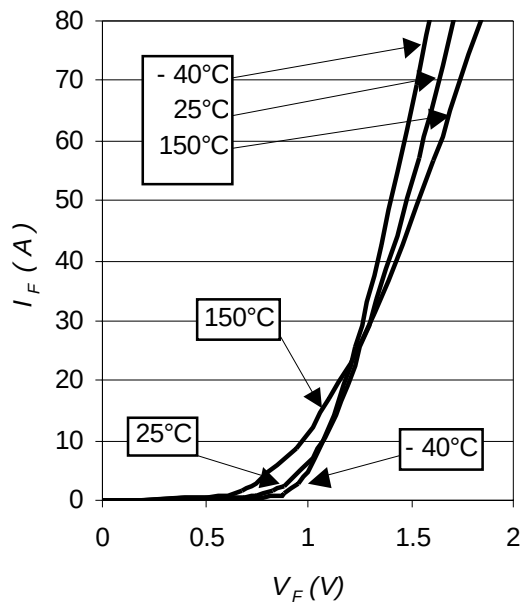


Fig. 3 - Diode Recovery Circuit

